Dependable VLSI platform using robust fabrics

Dependable VLSI platform (Evaluation Board)

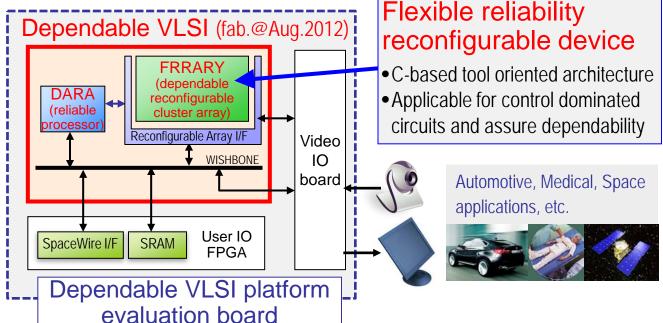
C-based Design Tool



- Reliability measure method
- Find some TMR modules to keep reliability under desirable level.



Synthesizes partial TMR circuits



- Robust Fabrics(Deliverable)
 - 40nm Standard Cell Design Environment and Variation-Tolerant D-FF
 - Smaller(4%), Faster(29%), Less variability(37%) than Conventional D-FF at 0.8V Operation.
 - Rad-Hard D-FF(Patent Pending)
 - No Soft-Error Observed in Neutron Irradiation Test

